







TMUX7221, TMUX7222

ZHCSNN1A - FEBRUARY 2023 **REVISED SEPTEMBER 2023**

具有闩锁效应抑制和 1.8V 逻辑电平的低 RON、1:1 (SPST)、 TMUX722x 44 V. 通道精密开关

1 特性

闩锁效应抑制

双电源电压范围: ±4.5V 至 ±22 V 单电源电压范围: 4.5V 至 44 V

低导通电阻: 2.1Ω

- 40°C 至 +125°C 工作温度

兼容 1.8V 逻辑电平

逻辑引脚具有集成的下拉电阻器

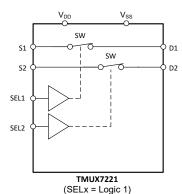
失效防护逻辑

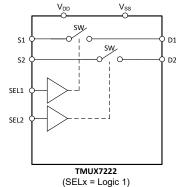
轨到轨运行

双向运行

2 应用

- 光纤网络
- 光学测试设备
- HVAC 控制器
- 超声波扫描仪
- 有源示波器探头
- 工厂自动化和工业控制
- 可编程逻辑控制器 (PLC)
- 模拟输入模块
- 半导体测试
- 患者监护和诊断
- 有线网络
- 数据采集系统





方框图

3 说明

TMUX722x 是具有闩锁效应抑制特性的互补金属氧化 物半导体 (CMOS) 开关,采用双通道 1:1 (SPST) 配 置。这些器件支持单电源(4.5V至44V)、双电源 (±4.5V 至 ±22 V)或非对称电源(例如, V_{DD} = 12V, V_{SS} = -5V)。TMUX722x 可在源极 (Sx) 和漏 极 (D) 引脚上支持从 V_{SS} 到 V_{DD} 范围的双向模拟和数 字信号。

TMUX722x 可以通过控制 SEL 引脚打开信号路径 1 (S1 至 D1)或信号路径 2(S2 至 D2)来启用或禁 用。所有逻辑控制输入均支持 1.8V 到 V_{DD} 的逻辑电 平, 当器件在有效电源电压范围内运行时, 可实现 TTL 和 CMOS 逻辑兼容性。失效防护逻辑电路允许先 在控制引脚上施加电压,然后在电源引脚上施加电压, 从而保护器件免受潜在的损害。详细信息请参见 节 8.3.5。

TMUX72xx 系列具有闩锁效应抑制特性,可防止器件 内寄生结构之间通常由过压事件引起的大电流不良事 件。闩锁状态通常会一直持续到电源轨关闭为止,并可 能导致器件故障。闩锁效应抑制特性使得 TMUX72xx 系列开关和多路复用器能够在恶劣的环境中使用。

封装信息

器件型号	封装 ⁽¹⁾	封装尺寸 ⁽²⁾
TMUX7221 TMUX7222	DGS (VSSOP , 10)	3mm × 4.9mm

如需了解所有可用封装,请参阅数据表末尾的封装选项附录。

(1)D2 (2) 封装尺寸(长×宽)为标称值,并包括引脚(如适用)。



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4 Revision History

注:以前版本的页码可能与当前版本的页码不同

С	Changes from Revision * (February 2023) to Revision A (April 2023)	Page
•	将数据表的状态从 <i>预告信息</i> 更改为 <i>量产数据</i>	1



5 Pin Configuration and Functions

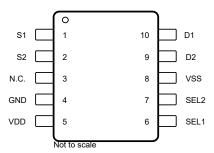


图 5-1. DGS Package, 10-Pin VSSOP (Top View)

表 5-1. Pin Functions

P	PIN TYPE(1)		DESCRIPTION ⁽²⁾
NAME	NO.	1 TPE(")	DESCRIPTION ⁽⁻⁾
S1	1	I/O	Source pin 1. Can be an input or output.
S2	2	I/O	Source pin 2. Can be an input or output.
N.C.	3	_	No internal connection. Can be shorted to GND or left floating.
GND	4	Р	Ground (0 V) reference
V _{DD}	5	Р	Positive power supply. This pin is the most positive power-supply potential. For reliable operation, connect a decoupling capacitor ranging from 0.1 μ F to 10 μ F between V _{DD} and GND.
SEL1	6	1	Logic control input, has internal pull-down resistor. Controls the switch connection. For more information, see # 8.5.
SEL2	7	ı	Logic control input, has internal pull-down resistor. Controls the switch connection. For more information, see # 8.5
V _{SS}	8	Р	Negative power supply. This pin is the most negative power-supply potential. In single-supply applications, this pin can be connected to ground. For reliable operation, connect a decoupling capacitor ranging from 0.1 μ F to 10 μ F between V _{SS} and GND.
D2	9	I/O	Drain pin 2. Can be an input or output.
D1	10	I/O	Drain pin 1. Can be an input or output.

- (1) I = input, O = output, I/O = input and output, P = power.
- (2) For what to do with unused pins, refer to 节 8.4.



6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range (unless otherwise noted)(1) (2)

		MIN	MAX	UNIT
V _{DD} - V _{SS}			48	V
V_{DD}	Supply voltage	- 0.5	48	V
V _{SS}		- 48	0.5	V
V _{SEL} or V _{EN}	Logic control input pin voltage (SELx)	- 0.5	48	V
I _{SEL} or I _{EN}	Logic control input pin current (SELx)	- 30	30	mA
V _S or V _D	Source or drain voltage (Sx, Dx)	V _{SS} - 0.5	V _{DD} +0.5	V
I _{IK}	Diode clamp current ⁽³⁾	- 30	30	mA
I _S or I _{D (CONT)}	Source or drain continuous current (Sx, Dx)		I _{DC} + 10 % ⁽⁴⁾	mA
T _A	Ambient temperature	- 55	150	°C
T _{stg}	Storage temperature	- 65	150	°C
T _J	Junction temperature		150	°C
P _{tot}	Total power dissipation (VSSOP) ⁽⁵⁾		450	mW

⁽¹⁾ Operation outside the Absolute Maximum Rating may cause permanent device damage. Absolute Maximum Rating do not imply functional operation of the device at these or any other conditions beyond those listed under Recommended Operating Condition. If used outside the Recommended Operating Condition but within the Absolute Maximum Rating, the device may not be fully functional, and this may affect device reliability, functionality, performance, and shorten the device lifetime.

- (2) All voltages are with respect to ground, unless otherwise specified.
- (3) Pins are diode-clamped to the power-supply rails. Over voltage signals must be voltage and current limited to maximum ratings.
- (4) Refer to Source or Drain Continuous Current table for I_{DC} specifications.
- (5) For VSSOP package: P_{tot} derates linearly above $T_A = 70^{\circ}$ C by 6.7mW/°C.

6.2 ESD Ratings

			VALUE	UNIT
TMUX722x				
V	Electrostatio discharge	Human body model (HBM), per ANSI/ESDA/ JEDEC JS-001, all pins ⁽¹⁾	±2000	V
V _(ESD) Electrostatic discharge	Charged device model (CDM), per ANSI/ESDA/ JEDEC JS-002, all pins ⁽²⁾	±500	V	

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

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6.3 Thermal Information

		TMUX722x	
	THERMAL METRIC ⁽¹⁾	DGS (VSSOP)	UNIT
		10 PINS	
R ₀ JA	Junction-to-ambient thermal resistance	154.3	°C/W
R _{θ JC(top)}	Junction-to-case (top) thermal resistance	52.9	°C/W
R _{θ JB}	Junction-to-board thermal resistance	75.3	°C/W
Ψ_{JT}	Junction-to-top characterization parameter	5.9	°C/W
Ψ_{JB}	Junction-to-board characterization parameter	73.9	°C/W
R ₀ JC(bot)	Junction-to-case (bottom) thermal resistance	N/A	°C/W

⁽¹⁾ For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

6.4 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM MAX	UNIT
$V_{DD} - V_{SS}$ (1)	Power supply voltage differential	4.5	44	V
V_{DD}	Positive power supply voltage	4.5	44	V
V _S or V _D	Signal path input/output voltage (source or drain pin) (Sx, D)	V _{SS}	V_{DD}	V
V _{SEL} or V _{EN}	Address or enable pin voltage	0	44	V
I _S or I _{D (CONT)}	Source or drain continuous current (Sx, D)		I _{DC} ⁽²⁾	mA
T _A	Ambient temperature	- 40	125	°C

 V_{DD} and V_{SS} can be any value as long as 4.5 V \leq (V_{DD} - V_{SS}) \leq 44 V, and the minimum V_{DD} is met. Refer to *Source or Drain Continuous Current* table for I_{DC} specifications.

6.5 Source or Drain Continuous Current

at supply voltage of V_{DD} ± 10%, V_{SS} ± 10 % (unless otherwise noted)

CONTINU	OUS CURRENT PER CHANNEL (I _{DC}) (2)	T _Δ = 25°C	T _Δ = 85°C	T _Δ = 125°C	UNIT
PACKAGE	PACKAGE TEST CONDITIONS		1A - 65 C	1A - 125 C	ONII
	+44 V Single Supply ⁽¹⁾	380	260	130	mA
DGS (VSSOP)	±15 V Dual Supply	380	260	130	mA
DG3 (V330F)	+12 V Single Supply	280	190	100	mA
	±5 V Dual Supply	240	160	90	mA

Specified for nominal supply voltage only.

Refer to Total power dissipation (Ptot) limits in Absolute Maximum Ratings table that must be followed with max continuous current specification.



6.6 ±15 V Dual Supply: Electrical Characteristics

 $V_{DD} = +15 \text{ V} \pm 10\%, \ V_{SS} = -15 \text{ V} \pm 10\%, \ \text{GND} = 0 \text{ V} \ \text{(unless otherwise noted)}$ Typical at $V_{DD} = +15 \text{ V}, \ V_{SS} = -15 \text{ V}, \ T_A = 25 ^{\circ}\text{C} \ \text{(unless otherwise noted)}$

	PARAMETER	TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT
ANALOG	SWITCH						
			25°C		2.1	2.9	Ω
R _{ON}	On-resistance	$V_S = -10 \text{ V to } +10 \text{ V}$ $I_D = -10 \text{ mA}$	- 40°C to +85°C			3.8	Ω
		lig – To tilik	- 40°C to +125°C			4.5	Ω
			25°C		0.05	0.25	Ω
ΔR_{ON}	On-resistance mismatch between channels	$V_S = -10 \text{ V to } +10 \text{ V}$ $I_D = -10 \text{ mA}$	- 40°C to +85°C			0.3	Ω
	ond moio	10 - 10 HIA	- 40°C to +125°C			0.35	Ω
			25°C		0.5	0.6	Ω
R _{ON FLAT}	On-resistance flatness	$V_S = -10 \text{ V to } +10 \text{ V}$ $I_S = -10 \text{ mA}$	- 40°C to +85°C			3.8 4.5 0.25 0.3 0.35 0.6 0.7 0.85 1.6 15 1.6 15 1.6 15 44 0.8 2.5	Ω
		IS - IOTIA	- 40°C to +125°C			0.85	Ω
R _{ON DRIFT}	On-resistance drift	$V_S = 0 \text{ V}, I_S = -10 \text{ mA}$	- 40°C to +125°C		0.01		Ω/°C
		V _{DD} = 16.5 V, V _{SS} = -16.5 V	25°C	- 0.15	0.05	0.15	nA
I _{S(OFF)}	Source off leakage current ⁽¹⁾	Switch state is off $V_S = +10 \text{ V} / -10 \text{ V}$	- 40°C to +85°C	- 1.6		1.6	nA
		$V_D = -10 \text{ V} / + 10 \text{ V}$	- 40°C to +125°C	- 15		1 2.9 3.8 4.5 5 0.25 0.3 0.35 5 0.6 0.7 0.85 1 5 0.15 1.6 15 5 0.15 1.6 15 5 0.15 1.6 15 5 0.15 1.6 15 5 0.15 1.6 15 5 0.15 1.6 15 5 0.15 1.6 1.5 1.6 1.5 1.6 1.5 1.6 1.5 1.6 1.5 1.6 1.5 1.6 1.5 1.6 1.5 1.6 1.5 1.6 1.5 1.6 1.5 1.6 1.5 1.6 1.5 1.6 1.5 1.6 1.5 1.6 1.5 1.5 1.6 1.5 1.5 1.6 1.5 1.5 1.5 1.6 1.5 1.5 1.5 1.5 1.5 1.5 1.5 1.5 1.5 1.5	nA
		V _{DD} = 16.5 V, V _{SS} = -16.5 V	25°C	- 0.15	0.05	0.15	nA
I _{D(OFF)}	Drain off leakage current ⁽¹⁾	Switch state is off V _S = +10 V / - 10 V V _D = -10 V / + 10 V	- 40°C to +85°C	- 1.6		1.6	nA
			- 40°C to +125°C	- 15		15	nA
			25°C	- 0.15	0.05	0.15	nA
ARON Con-resistar channels RON FLAT Con-resistar RON DRIFT Con-resistar Is(OFF) Source off Ib(OFF) Drain off leading to the control of th	Channel on leakage current ⁽²⁾	V_{DD} = 16.5 V, V_{SS} = -16.5 V Switch state is on	- 40°C to +85°C	- 1.6		1.6	nA
		$V_S = V_D = \pm 10 \text{ V}$	- 40°C to +125°C	- 15		15	nA
LOGIC IN	PUTS (SEL / EN pins)						
V _{IH}	Logic voltage high		- 40°C to +125°C	1.3		44	V
V _{IL}	Logic voltage low		- 40°C to +125°C	0		8.0	V
I _{IH}	Input leakage current		- 40°C to +125°C		1	2.5	μA
I _{IL}	Input leakage current		- 40°C to +125°C	- 0.1	- 0.005		μA
C _{IN}	Logic input capacitance		- 40°C to +125°C		3.5		pF
POWER S	SUPPLY						
			25°C		30	47	μA
I _{DD}	V _{DD} supply current	$V_{DD} = 16.5 \text{ V}, V_{SS} = -16.5 \text{ V}$ Logic inputs = 0 V, 5 V, or V_{DD}	- 40°C to +85°C			55	μA
		20g.5pato 0 v, 0 v, 01 v DD	- 40°C to +125°C		- 0.15 0.05 0.15 - 1.6 1.6 - 15 15 - 0.15 0.05 0.15 - 1.6 1.6 - 15 15 1.3 44 0 0.8 1 2.5 - 0.1 - 0.005 3.5 30 47 55 72 7 7 15 20	μA	
			25°C		7	15	μA
I _{SS}	V _{SS} supply current	V_{DD} = 16.5 V, V_{SS} = -16.5 V Logic inputs = 0 V, 5 V, or V_{DD}	- 40°C to +85°C			20	μA
		Logio inputo o v, o v, oi v DD	- 40°C to +125°C		,	30	μA

When V_S is positive, V_D is negative, or when V_S is negative, V_D is positive.

When V_S is at a voltage potential, V_D is floating, or when V_D is at a voltage potential, V_S is floating.

6.7 ±15 V Dual Supply: Switching Characteristics

 $V_{DD} = +15~V \pm 10\%,~V_{SS} = -15~V \pm 10\%,~GND = 0~V~(unless~otherwise~noted)$ Typical at $V_{DD} = +15~V,~V_{SS} = -15~V,~T_A = 25~C~(unless~otherwise~noted)$

	PARAMETER	TEST CONDITIONS	T _A	MIN TYP	MAX	UNIT
			25°C	145	180	ns
t _{ON}	Turn-on time from control input	$V_S = 10 \text{ V}$ $R_1 = 300 \Omega, C_1 = 35 \text{ pF}$	- 40°C to +85°C		190	ns
		11t 000 ss , OL 00 pi	- 40°C to +125°C		145 180 190 200 100 180 195 210 0.19 0.2 0.2 500 -15 - 70 - 50 - 114 - 93 45 - 0.18 - 71 0.0005	ns
			25°C	100	180	ns
t _{OFF}	Turn-off time from control input	$V_S = 10 \text{ V}$ $R_1 = 300 \Omega$, $C_1 = 35 \text{ pF}$	- 40°C to +85°C		195	ns
		11, 000 11, OL 00 PI	- 40°C to +125°C		145 180 190 200 100 180 195 210 0.19 0.2 0.2 500 -15 - 70 - 50 - 114 - 93 45 - 0.18 - 71 0.0005	ns
			25°C	0.19		ms
t _{ON (VDD)}	Device turn on time (V _{DD} to output)	V_{DD} rise time = 1 μs R_L = 300 Ω , C_L = 35 pF	- 40°C to +85°C	0.2		ms
	(Tob to surpar)	11, 000 11, OL 00 PI	- 40°C to +125°C	0.2		ms
t _{PD}	Propagation delay	$R_L = 50 \Omega$, $C_L = 5 pF$	25°C	500		ps
Q _{INJ}	Charge injection	V _S = 0 V, C _L = 100 pF	25°C	-15		рС
O _{ISO}	Off-isolation	R_L = 50 Ω , C_L = 5 pF V_S = 0 V, f = 100 kHz	25°C	- 70		dB
O _{ISO}	Off-isolation	R_L = 50 Ω , C_L = 5 pF V_S = 0 V, f = 1 MHz	25°C	- 50		dB
X _{TALK}	Crosstalk	R_L = 50 Ω , C_L = 5 pF V_S = 0 V, f = 100 kHz	25°C	- 114		dB
X _{TALK}	Crosstalk	R_L = 50 Ω , C_L = 5 pF V_S = 0 V, f = 1MHz	25°C	- 93		dB
BW	− 3dB Bandwidth	R_L = 50 Ω , C_L = 5 pF V_S = 0 V	25°C	45		MHz
IL	Insertion loss	R_L = 50 Ω , C_L = 5 pF V_S = 0 V, f = 1 MHz	25°C	- 0.18		dB
ACPSRR	AC Power Supply Rejection Ratio	V_{PP} = 0.62 V on V_{DD} and V_{SS} R_L = 50 Ω , C_L = 5 pF, f = 1 MHz	25°C	- 71		dB
THD+N	Total Harmonic Distortion + Noise	V_{PP} = 15 V, V_{BIAS} = 0 V R_{L} = 10 k Ω , C_{L} = 5 pF, f = 20 Hz to 20 kHz	25°C	0.0005		%
C _{S(OFF)}	Source off capacitance	V _S = 0 V, f = 1 MHz	25°C	25		pF
C _{D(OFF)}	Drain off capacitance	V _S = 0 V, f = 1 MHz	25°C	33		pF
C _{S(ON),} C _{D(ON)}	On capacitance	V _S = 0 V, f = 1 MHz	25°C	120		pF



6.8 ±20 V Dual Supply: Electrical Characteristics

 $V_{DD} = +20 \text{ V} \pm 10\%, \ V_{SS} = -20 \text{ V} \pm 10\%, \ \text{GND} = 0 \text{ V} \ \text{(unless otherwise noted)}$ Typical at $V_{DD} = +20 \text{ V}, \ V_{SS} = -20 \text{ V}, \ T_A = 25 ^{\circ}\text{C} \ \text{(unless otherwise noted)}$

	PARAMETER	TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT
ANALOG	SWITCH						
			25°C		1.9	2.7	Ω
R _{ON}	On-resistance	$V_S = -15 \text{ V to } +15 \text{ V}$ $I_D = -10 \text{ mA}$	- 40°C to +85°C			3.5	Ω
		10 TO TITA	- 40°C to +125°C			4.2	Ω
			25°C		0.04	0.22	Ω
∆ R _{ON}	On-resistance mismatch between channels	$V_S = -15 \text{ V to } +15 \text{ V}$ $I_D = -10 \text{ mA}$	- 40°C to +85°C			0.28	Ω
	orial mole	ID - TO MA	- 40°C to +125°C			0.3	Ω
			25°C		0.3	0.75	Ω
R _{ON FLAT}	On-resistance flatness	$V_S = -15 \text{ V to } +15 \text{ V}$ $I_S = -10 \text{ mA}$	- 40°C to +85°C			2.7 3.5 4.2 0.22 0.28 0.3	Ω
			- 40°C to +125°C				Ω
R _{ON DRIFT}	On-resistance drift	$V_S = 0 \text{ V}, I_S = -10 \text{ mA}$	- 40°C to +125°C		0.009		Ω/°C
		V _{DD} = 22 V, V _{SS} = -22 V	25°C	- 1.5	0.05	1.5	nA
I _{S(OFF)}	Source off leakage current ⁽¹⁾	Switch state is off $V_S = +15 \text{ V} / -15 \text{ V}$ $V_D = -15 \text{ V} / +15 \text{ V}$	- 40°C to +85°C	- 4		4	nA
			- 40°C to +125°C	- 24		24	nA
		V _{DD} = 22 V, V _{SS} = -22 V	25°C	- 1.5	0.05	1.5	nA
D(O(1)	Drain off leakage current ⁽¹⁾	Switch state is off $V_S = +15 \text{ V} / -15 \text{ V}$	- 40°C to +85°C	- 4		4	nA
		$V_D = -15 \text{ V} / + 15 \text{ V}$	- 40°C to +125°C	- 24		24	nA
		V - 22 V V - 22 V	25°C	- 1.5	0.05	1.5	nA
I _{S(ON)}	Channel on leakage current ⁽²⁾	V_{DD} = 22 V, V_{SS} = -22 V Switch state is on	- 40°C to +85°C	- 4		4	nA
I _{D(ON)}		$V_S = V_D = \pm 15 \text{ V}$	- 40°C to +125°C	- 24		24	nA
LOGIC IN	PUTS (SEL / EN pins)						
V _{IH}	Logic voltage high		- 40°C to +125°C	1.3		44	V
V _{IL}	Logic voltage low		- 40°C to +125°C	0		0.8	V
I _{IH}	Input leakage current		- 40°C to +125°C		0.5	2	μA
I _{IL}	Input leakage current		- 40°C to +125°C	- 0.1	- 0.005		μA
C _{IN}	Logic input capacitance		- 40°C to +125°C		3.5		pF
POWER S	SUPPLY						
			25°C		38	55	μA
I_{DD}	V _{DD} supply current	$V_{DD} = 22 \text{ V}, V_{SS} = -22 \text{ V}$ Logic inputs = 0 V, 5 V, or V_{DD}	- 40°C to +85°C			61	μΑ
		20g.0pato 0 v, 0 v, 01 v DD	- 40°C to +125°C		4.2 0.04 0.22 0.28 0.3 0.3 0.75 0.9 1.2 0.009 0.05 1.5 4 24 0.05 1.5 4 24 0.05 1.5 4 24 0.05 1.5 38 55 61 81 8 19	μΑ	
			25°C		8	15	μA
I _{SS}	V _{SS} supply current	V_{DD} = 22 V, V_{SS} = -22 V Logic inputs = 0 V, 5 V, or V_{DD}	- 40°C to +85°C			19	μA
			- 40°C to +125°C			37	μA

When V_S is positive, V_D is negative, or when V_S is negative, V_D is positive.

⁽²⁾ When V_S is at a voltage potential, V_D is floating, or when V_D is at a voltage potential, V_S is floating.

6.9 ±20 V Dual Supply: Switching Characteristics

 $V_{DD} = +20 \text{ V} \pm 10\%, V_{SS} = -20 \text{ V} \pm 10\%, \text{GND} = 0 \text{ V (unless otherwise noted)}$ Typical at $V_{DD} = +20 \text{ V}, V_{SS} = -20 \text{ V}, T_A = 25 ^{\circ}\text{C}$ (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T _A	MIN TYP	MAX	UNIT
			25°C	110	170	ns
t _{ON}	Turn-on time from control input	$V_S = 10 \text{ V}$ $R_L = 300 \Omega$, $C_L = 35 \text{ pF}$	- 40°C to +85°C		185	ns
		11(- 300 ³² , O _L - 30 β1	- 40°C to +125°C		200	ns
			25°C	90	180	ns
t _{OFF}	Turn-off time from control input	$V_S = 10 \text{ V}$ $R_I = 300 \Omega$, $C_I = 35 \text{ pF}$	- 40°C to +85°C		190	ns
		11. 000 , OL 00 PI	- 40°C to +125°C		200	ns
			25°C	0.18		ms
t _{ON (VDD)}	Device turn on time (V _{DD} to output)	V_{DD} rise time = 1 μs R_L = 300 Ω , C_L = 35 pF	- 40°C to +85°C	0.2		ms
	(100)	,	- 40°C to +125°C	0.2		ms
t _{PD}	Propagation delay	$R_L = 50 \Omega$, $C_L = 5 pF$	25°C	500		ps
Q _{INJ}	Charge injection	V _S = 0 V, C _L = 100 pF	25°C	-20		рС
O _{ISO}	Off-isolation	R_L = 50 Ω , C_L = 5 pF V_S = 0 V, f = 100 kHz	25°C	- 70		dB
O _{ISO}	Off-isolation	R_L = 50 Ω , C_L = 5 pF V_S = 0 V, f = 1 MHz	25°C	- 50		dB
X _{TALK}	Crosstalk	R_L = 50 Ω , C_L = 5 pF V_S = 0 V, f = 100 kHz	25°C	- 112		dB
X _{TALK}	Crosstalk	R_L = 50 Ω , C_L = 5 pF V_S = 0 V, f = 1MHz	25°C	- 93		dB
BW	- 3dB Bandwidth	R_L = 50 Ω , C_L = 5 pF V_S = 0 V	25°C	45		MHz
IL	Insertion loss	R_L = 50 Ω , C_L = 5 pF V_S = 0 V, f = 1 MHz	25°C	- 0.16		dB
ACPSRR	AC Power Supply Rejection Ratio	V_{PP} = 0.62 V on V_{DD} and V_{SS} R_L = 50 Ω , C_L = 5 pF, f = 1 MHz	25°C	- 69		dB
THD+N	Total Harmonic Distortion + Noise	$V_{PP} = 20 \text{ V}, V_{BIAS} = 0 \text{ V}$ $R_L = 10 \text{ k}\Omega$, $C_L = 5 \text{ pF}$, f = 20 Hz to 20 kHz	25°C	0.0005		%
C _{S(OFF)}	Source off capacitance	V _S = 0 V, f = 1 MHz	25°C	25		pF
C _{D(OFF)}	Drain off capacitance	V _S = 0 V, f = 1 MHz	25°C	32		pF
C _{S(ON),} C _{D(ON)}	On capacitance	V _S = 0 V, f = 1 MHz	25°C	120		pF



6.10 44 V Single Supply: Electrical Characteristics

 V_{DD} = +44 V, V_{SS} = 0 V, GND = 0 V (unless otherwise noted)

Typical at V_{DD} = +44 V, V_{SS} = 0 V, T_A = 25 $^{\circ}$ C (unless otherwise noted)

PARAMETER		TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT
ANALOG	SWITCH						
			25°C		2.2	2.8	Ω
R _{ON}	On-resistance	$V_S = 0 \text{ V to } 40 \text{ V}$ $I_D = -10 \text{ mA}$	- 40°C to +85°C			3.6	Ω
		ID - TO TILA	- 40°C to +125°C			4.2	Ω
			25°C		0.1	0.23	Ω
ΔR_{ON}	On-resistance mismatch between channels	V _S = 0 V to 40 V I _D = - 10 mA	- 40°C to +85°C			0.3	Ω
		10 10 11 11	- 40°C to +125°C			0.35	Ω
			25°C		0.2	1	Ω
R _{ON FLAT}	On-resistance flatness	$V_S = 0 \text{ V to } 40 \text{ V}$ $I_D = -10 \text{ mA}$	- 40°C to +85°C			1.3	Ω
		10 10 11 11	- 40°C to +125°C			1.5	Ω
R _{ON DRIFT}	On-resistance drift	V _S = 22 V, I _S = -10 mA	- 40°C to +125°C		0.008		Ω/°C
		V _{DD} = 44 V, V _{SS} = 0 V	25°C	- 5	0.05	5	nA
I _{S(OFF)}	Source off leakage current ⁽¹⁾	Switch state is off V _S = 40 V / 1 V	- 40°C to +85°C	- 10		10	nA
		V _D = 1 V / 40 V	- 40°C to +125°C	- 35		35	nA
		V _{DD} = 44 V, V _{SS} = 0 V	25°C	- 5	0.05	5	nA
I _{D(OFF)}	Drain off leakage current ⁽¹⁾	Switch state is off V _S = 40 V / 1 V	- 40°C to +85°C	- 10		10	nA
		$V_D = 1 \text{ V} / 40 \text{ V}$	- 40°C to +125°C	- 35		35	nA
		V _{DD} = 44 V, V _{SS} = 0 V	25°C	- 5	0.05	5	nA
$I_{S(ON)}$ $I_{D(ON)}$	Channel on leakage current ⁽²⁾	Switch state is on	- 40°C to +85°C	- 10		10	nA
-D(ON)		$V_S = V_D = 40 \text{ V or } 1 \text{ V}$	- 40°C to +125°C	- 35		35	nA
LOGIC IN	PUTS (SEL / EN pins)						
V _{IH}	Logic voltage high		- 40°C to +125°C	1.3		44	V
V _{IL}	Logic voltage low		- 40°C to +125°C	0		0.8	V
I _{IH}	Input leakage current		- 40°C to +125°C		0.5	2.75	μΑ
I _{IL}	Input leakage current		- 40°C to +125°C	- 0.1	- 0.005		μΑ
C _{IN}	Logic input capacitance		- 40°C to +125°C		3.5		pF
POWER S	SUPPLY	,		•			
			25°C		40	62	μΑ
I_{DD}	V _{DD} supply current	V_{DD} = 44 V, V_{SS} = 0 V Logic inputs = 0 V, 5 V, or V_{DD}	- 40°C to +85°C			70	μΑ
		0 1 - 7 - 7 - 100	- 40°C to +125°C			90	μΑ

⁽¹⁾ When V_S is positive, V_D is negative, or when V_S is negative, V_D is positive.

⁽²⁾ When V_S is at a voltage potential, V_D is floating, or when V_D is at a voltage potential, V_S is floating.

6.11 44 V Single Supply: Switching Characteristics

 V_{DD} = +44 V, V_{SS} = 0 V, GND = 0 V (unless otherwise noted)

Typical at V_{DD} = +44 V, V_{SS} = 0 V, T_A = 25 °C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT
			25°C		120	168	ns
t _{ON}	Turn-on time from control input	$V_S = 18 \text{ V}$ $R_L = 300 \Omega$, $C_L = 35 \text{ pF}$	- 40°C to +85°C			185	ns
		π. – 300 ω, οι – 30 μι	- 40°C to +125°C			195	ns
			25°C		120	180	ns
t _{OFF}	Turn-off time from control input	$V_S = 18 \text{ V}$ $R_L = 300 \Omega$, $C_L = 35 \text{ pF}$	- 40°C to +85°C			200	ns
		π. – 300 ω, οι – 30 μι	- 40°C to +125°C			205	ns
			25°C		0.15		ms
t _{ON (VDD)}	Device turn on time (V _{DD} to output)	V_{DD} rise time = 1 μs R_1 = 300 Ω , C_1 = 35 pF	- 40°C to +85°C		0.17		ms
, ,	(VDD to output)	π. – 300 ω, οι – 30 μι	- 40°C to +125°C		0.17		ms
t _{PD}	Propagation delay	$R_L = 50 \Omega$, $C_L = 5 pF$	25°C		500		ps
Q _{INJ}	Charge injection	V _S = 22 V, C _L = 100 pF	25°C		- 16		рС
O _{ISO}	Off-isolation	R_L = 50 Ω , C_L = 5 pF V_S = 6 V, f = 100 kHz	25°C		- 70		dB
O _{ISO}	Off-isolation	R_L = 50 Ω , C_L = 5 pF V_S = 6 V, f = 1 MHz	25°C		- 50		dB
X _{TALK}	Crosstalk	R_L = 50 Ω , C_L = 5 pF V_S = 6 V, f = 100 kHz	25°C		- 112		dB
X _{TALK}	Crosstalk	R_L = 50 Ω , C_L = 5 pF V_S = 6 V, f = 1MHz	25°C		- 93		dB
BW	- 3dB Bandwidth	R_L = 50 Ω , C_L = 5 pF V_S = 6 V	25°C		45		MHz
IL	Insertion loss	R_L = 50 Ω , C_L = 5 pF V_S = 6 V, f = 1 MHz	25°C	-	0.18		dB
ACPSRR	AC Power Supply Rejection Ratio	V_{PP} = 0.62 V on V_{DD} and V_{SS} R_L = 50 Ω , C_L = 5 pF, f = 1 MHz	25°C		- 70		dB
THD+N	Total Harmonic Distortion + Noise	V_{PP} = 22 V, V_{BIAS} = 22 V R_{L} = 10 k Ω , C_{L} = 5 pF, f = 20 Hz to 20 kHz	25°C	0.	0.0004		%
C _{S(OFF)}	Source off capacitance	V _S = 22 V, f = 1 MHz	25°C		25		pF
C _{D(OFF)}	Drain off capacitance	V _S = 22 V, f = 1 MHz	25°C		34		pF
C _{S(ON),} C _{D(ON)}	On capacitance	V _S = 22 V, f = 1 MHz	25°C		120		pF



6.12 12 V Single Supply: Electrical Characteristics

 V_{DD} = +12 V ± 10%, V_{SS} = 0 V, GND = 0 V (unless otherwise noted) Typical at V_{DD} = +12 V, V_{SS} = 0 V, T_A = 25°C (unless otherwise noted)

PARAMETER		TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT
ANALOG	SWITCH						
			25°C		4.6	6	Ω
R _{ON}	On-resistance	$V_S = 0 \text{ V to } 10 \text{ V}$ $I_D = -10 \text{ mA}$	- 40°C to +85°C			7.5	Ω
		ID - TOTILA	- 40°C to +125°C			8.4	Ω
			25°C		0.08	0.2	Ω
ΔR_{ON}	On-resistance mismatch between channels	$V_S = 0 \text{ V to } 10 \text{ V}$ $I_D = -10 \text{ mA}$	- 40°C to +85°C			0.32	Ω
	ond moio		- 40°C to +125°C			0.35	Ω
			25°C		1.2	2	Ω
R _{ON FLAT}	On-resistance flatness	$V_S = 0 \text{ V to } 10 \text{ V}$ $I_S = -10 \text{ mA}$	- 40°C to +85°C			2.2	Ω
		15 10 11111	- 40°C to +125°C			2.4	Ω
R _{ON DRIFT}	On-resistance drift	$V_S = 6 \text{ V}, I_S = -10 \text{ mA}$	- 40°C to +125°C		0.017		Ω/°C
		V _{DD} = 13.2 V, V _{SS} = 0 V	25°C	- 0.5	0.05	0.5	nA
I _{S(OFF)}	Source off leakage current ⁽¹⁾	Switch state is off V _S = 10 V / 1 V	- 40°C to +85°C	- 2		2	nA
		V _D = 1 V / 10 V	- 40°C to +125°C	- 12		12	nA
		V _{DD} = 13.2 V, V _{SS} = 0 V	25°C	- 0.5	0.05	0.5	nA
$I_{D(OFF)}$	Drain off leakage current ⁽¹⁾	Switch state is off V _S = 10 V / 1 V	- 40°C to +85°C	- 2		2	nA
		V _D = 1 V / 10 V	- 40°C to +125°C	- 12		12	nA
		V _{DD} = 13.2 V, V _{SS} = 0 V	25°C	- 0.5	0.05	0.5	nA
$I_{S(ON)}$ $I_{D(ON)}$	Channel on leakage current ⁽²⁾	Switch state is on	- 40°C to +85°C	- 2		2	nA
ID(ON)		$V_S = V_D = 10 \text{ V or } 1 \text{ V}$	- 40°C to +125°C	- 12		12	nA
LOGIC IN	PUTS (SEL / EN pins)						
V _{IH}	Logic voltage high		- 40°C to +125°C	1.3		44	V
V _{IL}	Logic voltage low		- 40°C to +125°C	0		0.8	V
I _{IH}	Input leakage current		- 40°C to +125°C		0.5	2	μA
I _{IL}	Input leakage current		- 40°C to +125°C	- 0.1	- 0.005		μA
C _{IN}	Logic input capacitance		- 40°C to +125°C		3.5		pF
POWER S	SUPPLY		•				
			25°C		30	40	μA
I_{DD}	V _{DD} supply current	V_{DD} = 13.2 V, V_{SS} = 0 V Logic inputs = 0 V, 5 V, or V_{DD}	- 40°C to +85°C			50	μA
		3 1-2 2 1, 2 1, 21 1, 20	- 40°C to +125°C			62	μA

When V_S is positive, V_D is negative, or when V_S is negative, V_D is positive.

When V_S is at a voltage potential, V_D is floating, or when V_D is at a voltage potential, V_S is floating.

6.13 12 V Single Supply: Switching Characteristics

 V_{DD} = +12 V ± 10%, V_{SS} = 0 V, GND = 0 V (unless otherwise noted)

Typical at V_{DD} = +12 V, V_{SS} = 0 V, T_A = 25°C (unless otherwise noted)

	PARAMETER	TEST CONDITIONS	T _A	MIN	TYP	MAX	UNIT
			25°C		120	180	ns
t _{ON}	Turn-on time from control input	$V_S = 8 V$ $R_L = 300 \Omega, C_L = 35 pF$	- 40°C to +85°C			210	ns
		π. – 300 ω, οι – 30 μι	- 40°C to +125°C			230	ns
			25°C		130	210	ns
t _{OFF}	Turn-off time from control input	$V_S = 8 V$ $R_L = 300 \Omega, C_L = 35 pF$	- 40°C to +85°C			235	ns
		π. – 300 ω, οι – 30 μι	- 40°C to +125°C			250	ns
			25°C		0.19		ms
t _{ON (VDD)}	Device turn on time (V _{DD} to output)	V_{DD} rise time = 1 μs R_1 = 300 Ω , C_1 = 35 pF	- 40°C to +85°C		0.2		ms
	(VDD to output)	1\(\(\begin{align*} \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \	- 40°C to +125°C		0.2		ms
t _{PD}	Propagation delay	$R_L = 50 \Omega$, $C_L = 5 pF$	25°C		500		ps
Q _{INJ}	Charge injection	V _S = 6 V, C _L = 100 pF	25°C	,	- 6		рС
O _{ISO}	Off-isolation	R_L = 50 Ω , C_L = 5 pF V_S = 6 V, f = 100 kHz	25°C		- 70		dB
O _{ISO}	Off-isolation	R_L = 50 Ω , C_L = 5 pF V_S = 6 V, f = 1 MHz	25°C		- 50		dB
X _{TALK}	Crosstalk	R_L = 50 Ω , C_L = 5 pF V_S = 6 V, f = 100 kHz	25°C		- 112		dB
X _{TALK}	Crosstalk	R_L = 50 Ω , C_L = 5 pF V_S = 6 V, f = 1MHz	25°C		- 93		dB
BW	- 3dB Bandwidth	R_L = 50 Ω , C_L = 5 pF V_S = 6 V	25°C		60		MHz
IL	Insertion loss	R_L = 50 Ω , C_L = 5 pF V_S = 6 V, f = 1 MHz	25°C		- 0.3		dB
ACPSRR	AC Power Supply Rejection Ratio	V_{PP} = 0.62 V on V_{DD} and V_{SS} R_L = 50 Ω , C_L = 5 pF, f = 1 MHz	25°C		- 76		dB
THD+N	Total Harmonic Distortion + Noise	$V_{PP} = 6 \text{ V}, V_{BIAS} = 6 \text{ V}$ $R_L = 10 \text{ k}\Omega$, $C_L = 5 \text{ pF}$, f = 20 Hz to 20 kHz	25°C	0	.0009		%
C _{S(OFF)}	Source off capacitance	V _S = 6 V, f = 1 MHz	25°C		30		pF
C _{D(OFF)}	Drain off capacitance	V _S = 6 V, f = 1 MHz	25°C		38		pF
C _{S(ON)} , C _{D(ON)}	On capacitance	V _S = 6 V, f = 1 MHz	25°C		110		pF



6.14 Typical Characteristics

at $T_A = 25$ °C

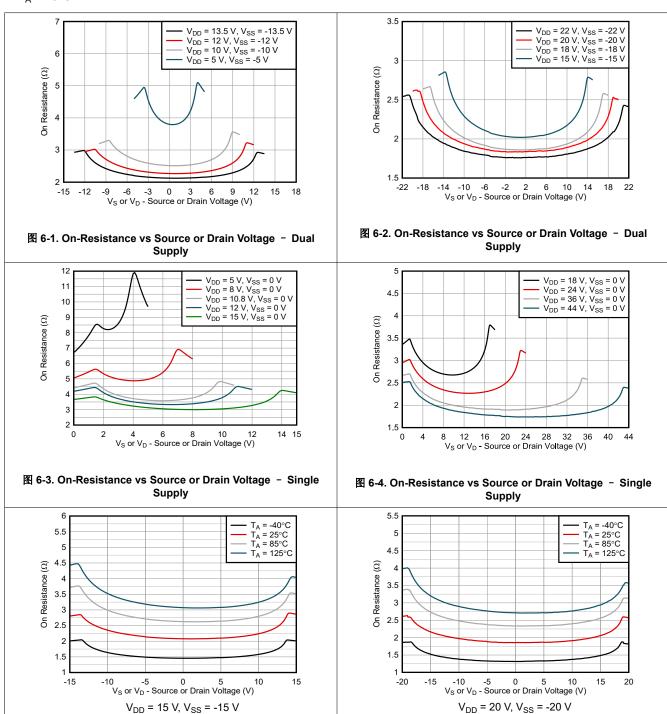


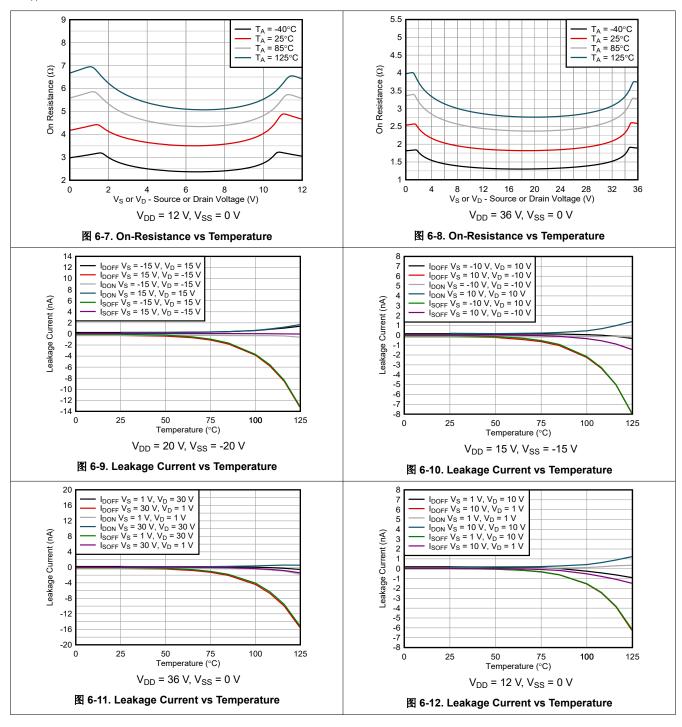
图 6-5. On-Resistance vs Temperature

English Data Sheet: SCDS444

图 6-6. On-Resistance vs Temperature

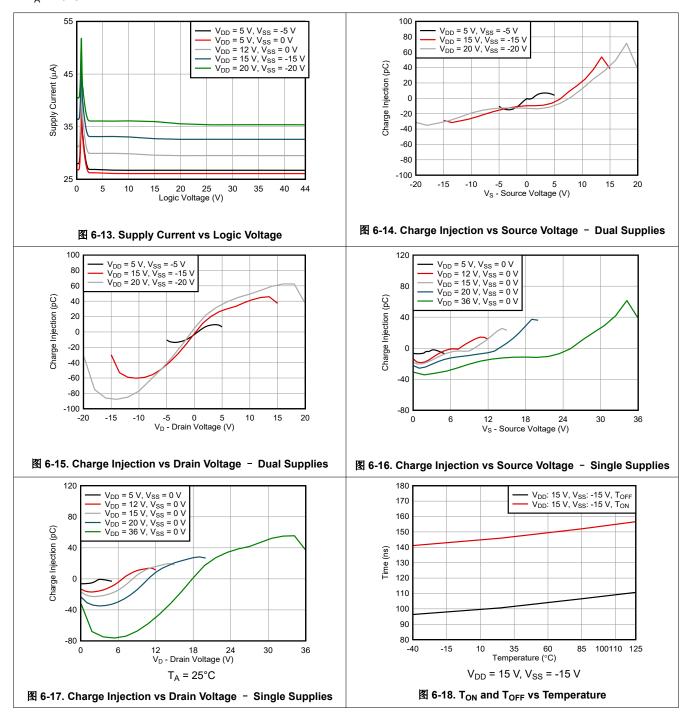


at $T_A = 25$ °C



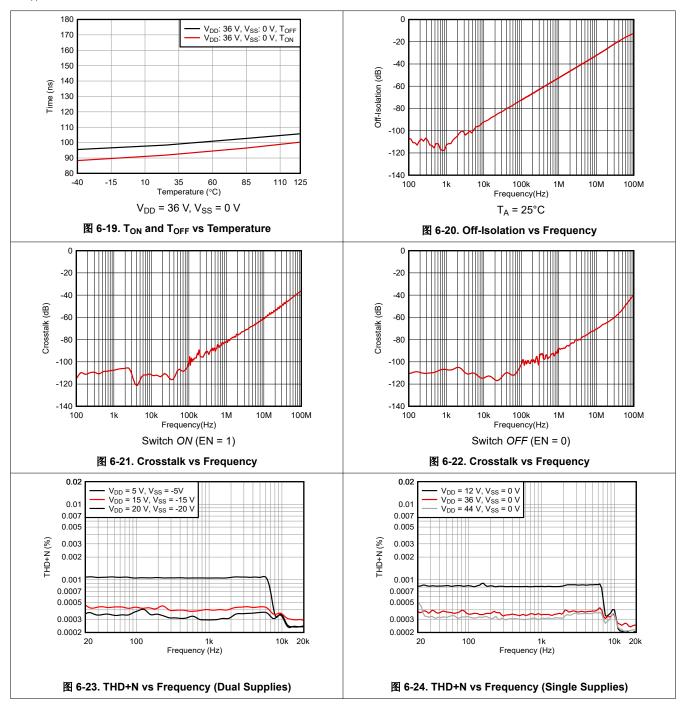


at $T_A = 25$ °C



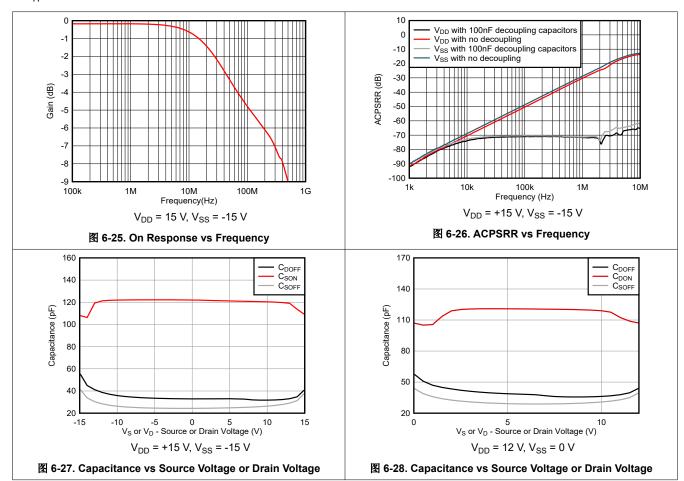


at $T_A = 25$ °C





at $T_A = 25$ °C



7 Parameter Measurement Information

7.1 On-Resistance

The on-resistance of a device is the ohmic resistance between the source (Sx) and drain (D) pins of the device. The on-resistance varies with input voltage and supply voltage. The symbol R_{ON} is used to denote on-resistance. 87-1 shows the measurement setup used to measure R_{ON} . Voltage (V) and current (I_{SD}) are measured using the following setup, where R_{ON} is computed as $R_{ON} = V / I_{SD}$:

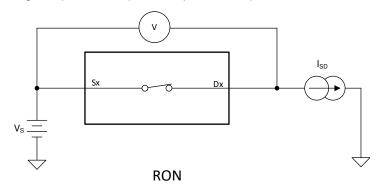


图 7-1. On-Resistance

7.2 Off-Leakage Current

There are two types of leakage currents associated with a switch during the off state:

- 1. Source off-leakage current.
- 2. Drain off-leakage current.

Source leakage current is defined as the leakage current flowing into or out of the source pin when the switch is off. This current is denoted by the symbol $I_{S(OFF)}$.

Drain leakage current is defined as the leakage current flowing into or out of the drain pin when the switch is off. This current is denoted by the symbol $I_{D(OFF)}$.

图 7-2 shows the setup used to measure both off-leakage currents.

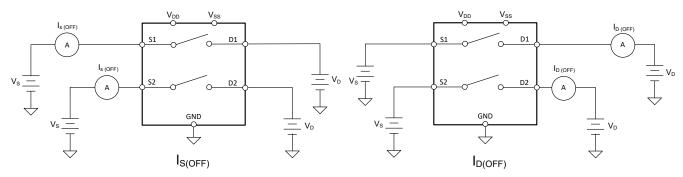


图 7-2. Off-Leakage Measurement Setup

7.3 On-Leakage Current

Source on-leakage current is defined as the leakage current flowing into or out of the source pin when the switch is on. This current is denoted by the symbol $I_{S(ON)}$.

Drain on-leakage current is defined as the leakage current flowing into or out of the drain pin when the switch is on. This current is denoted by the symbol $I_{D(ON)}$.

Either the source pin or drain pin is left floating during the measurement. $\boxed{8}$ 7-3 shows the circuit used for measuring the on-leakage current, denoted by $I_{S(ON)}$ or $I_{D(ON)}$.

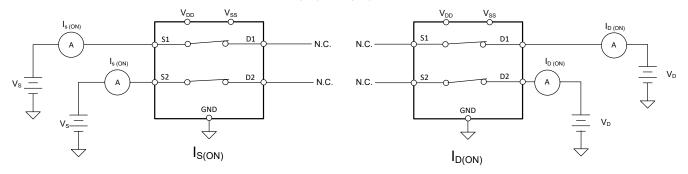


图 7-3. On-Leakage Measurement Setup

7.4 t_{ON(EN)} and t_{OFF(EN)}

Turn-on time is defined as the time taken by the output of the device to rise to 90% after the enable has risen past the logic threshold. The 90% measurement is utilized to provide the timing of the device. System level timing can then account for the time constant added from the load resistance and load capacitance. 47-4 shows the setup used to measure turn-on time, denoted by the symbol $t_{ON(EN)}$.

Turn-off time is defined as the time taken by the output of the device to fall to 10% after the enable has fallen past the logic threshold. The 10% measurement is utilized to provide the timing of the device. System level timing can then account for the time constant added from the load resistance and load capacitance. $\boxed{8}$ 7-4 shows the setup used to measure turn-off time, denoted by the symbol $t_{OFF(EN)}$.

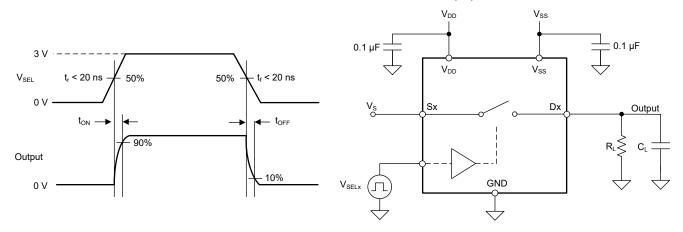


图 7-4. Turn-On and Turn-Off Time Measurement Setup

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7.5 t_{ON (VDD)} Time

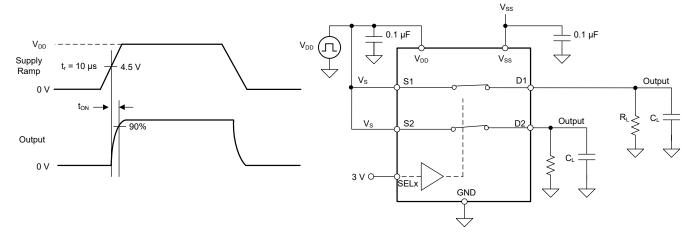


图 7-5. t_{ON (VDD)} Time Measurement Setup

7.6 Propagation Delay

Propagation delay is defined as the time taken by the output of the device to rise or fall 50% after the input signal has risen or fallen past the 50% threshold. $\boxed{8}$ 7-6 shows the setup used to measure propagation delay, denoted by the symbol t_{PD} .

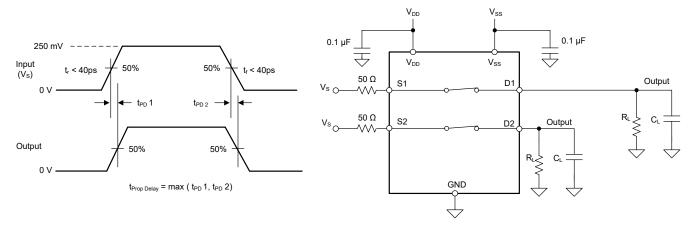


图 7-6. Propagation Delay Measurement Setup

7.7 Charge Injection

The TMUX722x has a transmission-gate topology. Any mismatch in capacitance between the NMOS and PMOS transistors results in a charge injected into the drain or source during the falling or rising edge of the gate signal. The amount of charge injected into the source or drain of the device is known as charge injection, and is denoted by the symbol Q_C . 87-7 shows the setup used to measure charge injection from source (Sx) to drain (D).

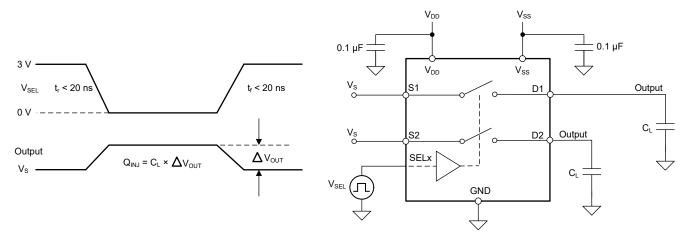


图 7-7. Charge-Injection Measurement Setup

7.8 Off Isolation

Off isolation is defined as the ratio of the signal at the drain pin (Dx) of the device when a signal is applied to the source pin (Sx) of an off-channel. The characteristic impedance, Z_0 , for the measurement is 50 Ω . \boxtimes 7-8 shows the setup used to measure off isolation. Use off isolation equation to compute off isolation.

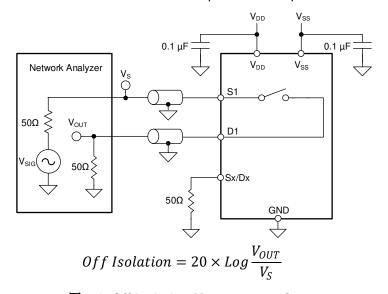


图 7-8. Off Isolation Measurement Setup

7.9 Crosstalk

Crosstalk is defined as the ratio of the signal at the drain pin (D) of a different channel, when a signal is applied at the source pin (Sx) of an on-channel. 图 7-9 shows the setup used to measure, and the equation used to calculate crosstalk.

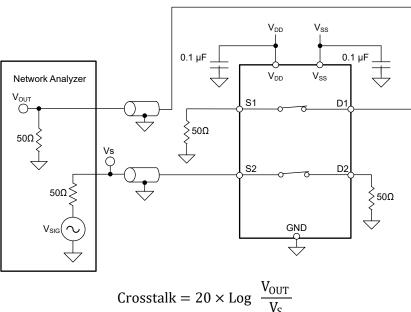


图 7-9. Crosstalk Measurement Setup

7.10 Bandwidth

Bandwidth is defined as the range of frequencies that are attenuated by less than 3 dB when the input is applied to the source pin (Sx) of an on-channel, and the output is measured at the drain pin (Dx) of the device. The characteristic impedance, Z_0 , for the measurement is 50 Ω . \boxtimes 7-10 shows the setup used to measure bandwidth.

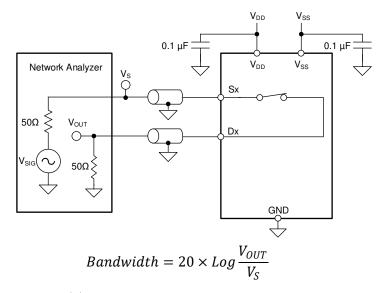


图 7-10. Bandwidth Measurement Setup

7.11 THD + Noise

The total harmonic distortion (THD) of a signal is a measurement of the harmonic distortion, and is defined as the ratio of the sum of the powers of all harmonic components to the power of the fundamental frequency at the mux output. The on-resistance of the device varies with the amplitude of the input signal and results in distortion when the drain pin is connected to a low-impedance load. Total harmonic distortion plus noise is denoted as THD + N.

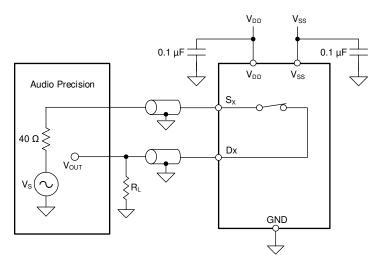


图 7-11. THD + N Measurement Setup

7.12 Power Supply Rejection Ratio (PSRR)

PSRR measures the ability of a device to prevent noise and spurious signals that appear on the supply voltage pin from coupling to the output of the switch. The DC voltage on the device supply is modulated by a sine wave of 100 mV_{PP} . The ratio of the amplitude of signal on the output to the amplitude of the modulated signal is the AC PSRR.

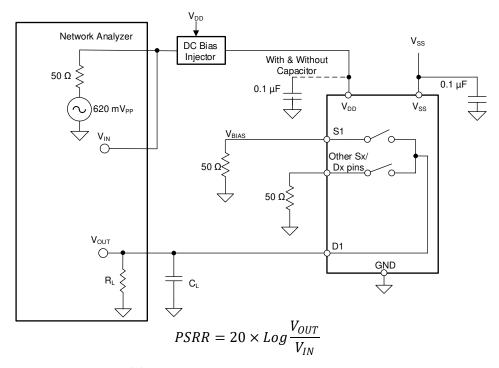


图 7-12. AC PSRR Measurement Setup

8 Detailed Description

8.1 Overview

The TMUX722x is a 1:1, 2-channel switch. Each input is turned on or turned off based on the state of the select line and enable pin.

8.2 Functional Block Diagram

图 8-1 shows the functional block diagram of the TMUX722x.

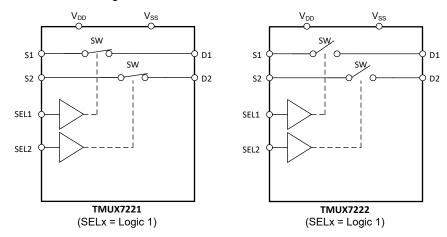


图 8-1. TMUX722x Functional Block Diagram

8.3 Feature Description

8.3.1 Bidirectional Operation

The TMUX722x conducts equally well from source (Sx) to drain (D) or from drain (D) to source (Sx). Each channel has very similar characteristics in both directions and supports both analog and digital signals.

8.3.2 Rail-to-Rail Operation

The valid signal path input and output voltage for TMUX722x ranges from V_{SS} to V_{DD}.

8.3.3 1.8 V Logic Compatible Inputs

The TMUX722x has 1.8 V logic compatible control for all logic control inputs. 1.8 V logic level inputs allows the device to interface with processors that have lower logic I/O rails and eliminates the need for an external translator, which saves both space and BOM cost. For more information on 1.8 V logic implementations, refer to Simplifying Design with 1.8 V logic Muxes and Switches.

8.3.4 Integrated Pull-Down Resistor on Logic Pins

The TMUX722x have internal weak pull-down resistors to GND so that the logic pins are not left floating. The value of this pull-down resistor is approximately 4 M Ω , but is clamped to about 1 μ A at higher voltages. This feature integrates up to four external components and reduces system size and cost.

8.3.5 Fail-Safe Logic

The TMUX722x supports Fail-Safe Logic on the control input pins (EN, SEL) allowing for operation up to 44 V above ground, regardless of the state of the supply pins. This feature allows voltages on the control pins to be applied before the supply pin, protecting the device from potential damage. Fail-Safe Logic minimizes system complexity by removing the need for power supply sequencing on the logic control pins. For example, the Fail-Safe Logic feature allows the logic input pins of the TMUX722x to be ramped to +44 V while V_{DD} and V_{SS} = 0 V. The logic control inputs are protected against positive faults of up to +44 V in powered-off condition, but do not offer protection against negative overvoltage conditions.

8.3.6 Latch-Up Immune

Latch-Up is a condition where a low impedance path is created between a supply pin and ground. This condition is caused by a trigger (current injection or overvoltage), but once activated, the low impedance path remains even after the trigger is no longer present. This low impedance path may cause system upset or catastrophic damage due to excessive current levels. The Latch-Up condition typically requires a power cycle to eliminate the low impedance path.

The TMUX722x family of devices are constructed on Silicon on Insulator (SOI) based process where an oxide layer is added between the PMOS and NMOS transistor of each CMOS switch to prevent parasitic structures from forming. The oxide layer is also known as an insulating trench and prevents triggering of latch up events due to overvoltage or current injections. The latch-up immunity feature allows the TMUX722x family of switches and multiplexers to be used in harsh environments.

8.3.7 Ultra-Low Charge Injection

The TMUX722x has a transmission gate topology, as shown in 🖺 8-2. Any mismatch in the stray capacitance associated with the NMOS and PMOS causes an output level change whenever the switch is opened or closed.

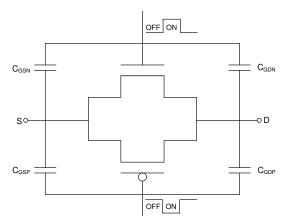


图 8-2. Transmission Gate Topology

The TMUX722x contains specialized architecture to reduce charge injection on the Drain (Dx). To further reduce charge injection in a sensitive application, a compensation capacitor (Cp) can be added on the Source (Sx). Doing this will push excess charge from the switch transition into the compensation capacitor on the Source (Sx) instead of the Drain (Dx). As a general rule, Cp should be 20x larger than the equivalent load capacitance on the Drain (Dx). Shows charge injection variation with different compensation capacitors on the Source side. This plot was captured on the TMUX7219 as part of the TMUX72xx family with a 100 pF load capacitance.

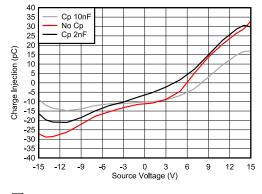


图 8-3. Charge Injection Compensation

8.4 Device Functional Modes

The TMUX722x devices have two independently selectable single-pole, single-throw switches that are turned-on or turned-off based on the state of the corresponding select pin. The control pins can be as high as 44 V.

The TMUX722x devices can be operated without any external components except for the supply decoupling capacitors. The SEL pins has internal pull-down resistor of 4 M Ω . If unused, tie the SEL pins to GND so that the device does not consume additional current as highlighted in *Implications of Slow or Floating CMOS Inputs*. Connect unused signal path inputs (S1, S2, D1, or D2) to GND.

8.5 Truth Tables

表 8-1 provides the truth tables for the TMUX722x.

表 8-1. TMUX7221 Truth Table

SEL x	CHANNEL x
0	Channel x OFF
1	Channel x ON

表 8-2. TMUX7222 Truth Table

SEL x	CHANNEL x
0	Channel x ON
1	Channel x OFF

9 Application and Implementation

备注

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes, as well as validating and testing their design implementation to confirm system functionality.

9.1 Application Information

TMUX722x is part of the precision switches and multiplexers family of devices. TMUX722x offers low RON, low on and off leakage currents and ultra-low charge injection performance. These properties make TMUX722x ideal for implementing high precision industrial systems requiring selection of one of two inputs or outputs.

9.2 Typical Applications

9.2.1 Switched Gain Amplifier - Discrete PGA

Switches and multiplexers are commonly used in the feedback path of amplifier circuits to provide configurable gain control. By using various resistor values on each switch path the TMUX722x allows the system to have multiple gain settings. An external resistor, ensures the amplifier isn't operating in an open loop configuration, and gives up to 4 gain settings. The leakage current, on-resistance, and charge injection performance of the TMUX722x are key specifications to evaluate when selecting a device for gain control.

For more information on how to use Tl's analog switches in Discrete Programmable Gain Amplifier (PGA) such as the impact of On-Capacitance, see *Choosing the Right Multiplexer for a Discrete Programmable Gain Amplifier (PGA)*

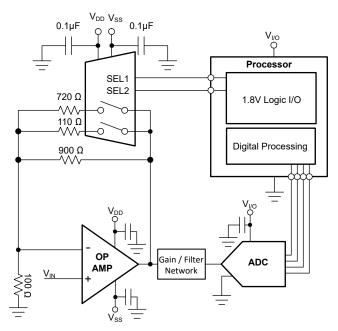


图 9-1. Gain Switching

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9.2.1.1 Design Requirements

For this design example, use the parameters listed in 节 9.2.1.1.

表 9-1. Design Parameters

PARAMETERS	VALUES
Supply (V _{DD})	15 V
Supply (V _{SS})	- 15 V
Input / Output signal range	-15 V to 15 V (Rail-to-Rail)
Control logic thresholds	1.8 V compatible

9.2.1.2 Detailed Design Procedure

The TMUX722x device can be operated without any external components except for the supply decoupling capacitors. All inputs signals passing through the switch must fall within the recommend operating conditions of the TMUX722x including signal range and continuous current. For this design example, with a supply of +15 V and -15 V, the signals can range from +15 V to -15 V when the device is powered.

The application shown in *Switching Gain Settings* demonstrates how to use the TMUX722x to control the feedback gain of a precision op-amp. This feedback design can very sensitive to induced voltage and current offsets. The TMUX722x has a typical On-leakage current of 100 pA which would lead to an accuracy well within 1% of a full scale 1 µA signal, thus minimizing errors from current offsets. The low On-Resistance of the TMUX722x leads to a low error in the feedback resistance and resulting gain, and also minimizes any voltage offsets.

表 9-2. Programmable Gain and Error

SEL1	SEL2	Gain	Gain Error
0	0	10x	0%
1	0	5x	0.13%
0	1	2x	0.16%

9.2.1.3 Application Curve

The TMUX722x is capable of switching signals with minimal distortion because of the ultra-low leakage currents and excellent on-resistance flatness.

9-2 shows how the on-resistance for the TMUX722x varies with different supply voltages.

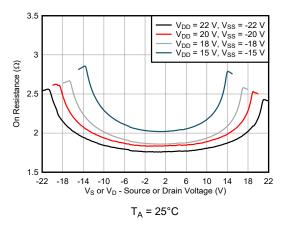


图 9-2. On-Resistance vs Source or Drain Voltage

9.3 Power Supply Recommendations

The TMUX722x operates across a wide supply range of ± 4.5 V to ± 22 V (4.5 V to 44 V in single-supply mode). The device also performs well with asymmetrical supplies such as $V_{DD} = 12$ V and $V_{SS} = -5$ V.

Power-supply bypassing improves noise margin and prevents switching noise propagation from the supply rails to other components. Good power-supply decoupling is important to achieve optimum performance. For improved supply noise immunity, use a supply decoupling capacitor ranging from 0.1 μ F to 10 μ F at both the V_{DD} and V_{SS} pins to ground. Place the bypass capacitors as close to the power supply pins of the device as possible using low-impedance connections. TI recommends using multi-layer ceramic chip capacitors (MLCCs) that offer low equivalent series resistance (ESR) and inductance (ESL) characteristics for power-supply decoupling purposes. For very sensitive systems, or for systems in harsh noise environments, avoiding the use of vias for connecting the capacitors to the device pins may offer superior noise immunity. The use of multiple vias in parallel lowers the overall inductance and is beneficial for connections to ground and power planes. Always ensure the ground (GND) connection is established before supplies are ramped.

9.4 Layout

9.4.1 Layout Guidelines

When a PCB trace turns a corner at a 90° angle, a reflection can occur. A reflection occurs primarily because of the change of width of the trace. At the apex of the turn, the trace width increases to 1.414 times the width. This increase upsets the transmission-line characteristics, especially the distributed capacitance and self – inductance of the trace which results in the reflection. Not all PCB traces can be straight and therefore some traces must turn corners.

9-3 shows progressively better techniques of rounding corners. Only the last example (BEST) maintains constant trace width and minimizes reflections.

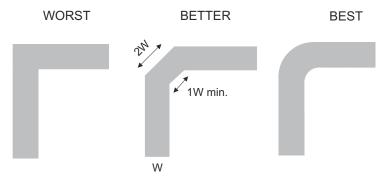


图 9-3. Trace Example

Route high-speed signals using a minimum of vias and corners which reduces signal reflections and impedance changes. When a via must be used, increase the clearance size around it to minimize its capacitance. Each via introduces discontinuities in the signal's transmission line and increases the chance of picking up interference from the other layers of the board. Be careful when designing test points, through-hole pins are not recommended at high frequencies.

Some key considerations are:

- For reliable operation, connect a decoupling capacitor ranging from 0.1 μF to 10 μF between VDD/VSS and GND. We recommend a 0.1 μF and 1 μF capacitor, placing the lowest value capacitor as close to the pin as possible. Make sure that the capacitor voltage rating is sufficient for the supply voltage.
- · Keep the input lines as short as possible.
- Use a solid ground plane to help reduce electromagnetic interference (EMI) noise pickup.
- Do not run sensitive analog traces in parallel with digital traces. Avoid crossing digital and analog traces if possible, and only make perpendicular crossings when necessary.
- Using multiple vias in parallel will lower the overall inductance and is beneficial for connection to ground planes.

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9.4.2 Layout Example

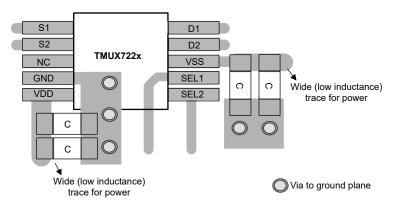


图 9-4. TMUX722x Layout Example



10 Device and Documentation Support

10.1 Documentation Support

10.1.1 Related Documentation

For related documentation, see the following:

- Texas Instruments, Improve Stability Issues with Low CON Multiplexers.
- Texas Instruments, Improving Signal Measurement Accuracy in Automated Test Equipment.
- Texas Instruments, Multiplexers and Signal Switches Glossary.
- Texas Instruments, QFN/SON PCB Attachment.
- Texas Instruments, Quad Flat pack No-Lead Logic Packages.
- Texas Instruments, Simplifying Design with 1.8 V logic Muxes and Switches.
- Texas Instruments, System-Level Protection for High-Voltage Analog Multiplexers.
- Texas Instruments, True Differential, 4 x 2 MUX, Analog Front End, Simultaneous-Sampling ADC Circuit.

10.2 Receiving Notification of Documentation Updates

To receive notification of documentation updates, navigate to the device product folder on ti.com. In the upper right corner, click on *Alert me* to register and receive a weekly digest of any product information that has changed. For change details, review the revision history included in any revised document.

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10.6 术语表

TI术语表本术语表列出并解释了术语、首字母缩略词和定义。

11 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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PACKAGING INFORMATION

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
PTMUX7221DGSR	ACTIVE	VSSOP	DGS	10	2500	TBD	Call TI	Call TI	-40 to 125		Samples
PTMUX7222DGSR	ACTIVE	VSSOP	DGS	10	2500	TBD	Call TI	Call TI	-40 to 125		Samples
TMUX7221DGSR	ACTIVE	VSSOP	DGS	10	2500	RoHS & Green	SN	Level-2-260C-1 YEAR	-40 to 125	TM221	Samples
TMUX7222DGSR	ACTIVE	VSSOP	DGS	10	2500	RoHS & Green	SN	Level-2-260C-1 YEAR	-40 to 125	TM222	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

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NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

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OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

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- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

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TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TMUX7221DGSR	VSSOP	DGS	10	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
TMUX7222DGSR	VSSOP	DGS	10	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1

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*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TMUX7221DGSR	VSSOP	DGS	10	2500	366.0	364.0	50.0
TMUX7222DGSR	VSSOP	DGS	10	2500	366.0	364.0	50.0

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